

## Question 1

Find NPN, PNP, SCR (NPNP) devices in the process profile from CMOS inverter cross section (next page; draw the 3 devices overtop of the CMOS process cross-section) and propose a circuit technique to avoid CMOS SCR latchup.

## Question 2

Suppose you broke the loop between the PNP collector and NPN base of an SCR: describe  $I_{Cnpn} = f(I_{Bnpn})$  for this 2-BJT circuit with  $V_{DD} = 1.2\text{ V}$ , each with  $\beta = 10$ . Describe what happens in the closed loop.

## Question 3

Create a static CMOS schematic, and sticks layout of

$x \leq a \text{ NAND } b; y \leq b \text{ NAND } c;$

Look at the two transistor schematics. Optimize and count the number of:

1. transistors
2. diffusion regions
3. metal-diffusion contacts

## Question 4